Se	earch Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/674,418	YAMAKAWA ET AL.	
Examiner	Art Unit	
Jean W. Désir	2622	

SEARCHED				
Class	Subclass	Date	Examiner	
348	607	8/17/0	m	
	620	625		
	627	670		
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
348	627.2	26.1,6/2	7/07
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345	611		
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SEARCH NOT			
(INCLUDING SEARCH	DATE	EXMR	•
EAST	8/17/	106	
Discussed in EEN	8/16/0	6	
Interference Search	6/27	107 M	
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